



# RF Power Field Effect Transistors

## N-Channel Enhancement-Mode Lateral MOSFETs

Designed for CDMA base station applications with frequencies from 2300 to 2400 MHz. Suitable for WiMAX, WiBro and multicarrier amplifier applications. To be used in Class AB and Class C for WLL applications.

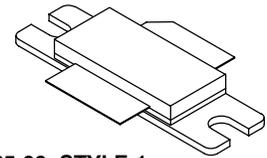
- Typical 2-Carrier W-CDMA Performance:  $V_{DD} = 28$  Volts,  $I_{DQ} = 1000$  mA,  $P_{out} = 20$  Watts Avg.,  $f = 2390$  MHz, Channel Bandwidth = 3.84 MHz, PAR = 8.5 dB @ 0.01% Probability on CCDF.  
 Power Gain — 15.4 dB  
 Drain Efficiency — 23.5%  
 IM3 @ 10 MHz Offset — -37 dBc @ 3.84 MHz Channel Bandwidth  
 ACPR @ 5 MHz Offset — -40.5 dBc @ 3.84 MHz Channel Bandwidth
- Capable of Handling 10:1 VSWR, @ 28 Vdc, 2390 MHz, 100 Watts CW Output Power

### Features

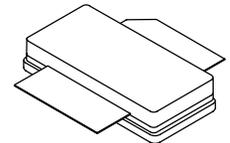
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Qualified Up to a Maximum of 32  $V_{DD}$  Operation
- Integrated ESD Protection
- Designed for Lower Memory Effects and Wide Instantaneous Bandwidth Applications
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

**MRF6S23100HR3**  
**MRF6S23100HSR3**

**2300-2400 MHz, 20 W AVG., 28 V**  
**2 x W-CDMA**  
**LATERAL N-CHANNEL**  
**RF POWER MOSFETs**



**CASE 465-06, STYLE 1**  
**NI-780**  
**MRF6S23100HR3**



**CASE 465A-06, STYLE 1**  
**NI-780S**  
**MRF6S23100HSR3**

**Table 1. Maximum Ratings**

| Rating                               | Symbol    | Value       | Unit |
|--------------------------------------|-----------|-------------|------|
| Drain-Source Voltage                 | $V_{DSS}$ | -0.5, +68   | Vdc  |
| Gate-Source Voltage                  | $V_{GS}$  | -0.5, +12   | Vdc  |
| Storage Temperature Range            | $T_{stg}$ | -65 to +150 | °C   |
| Case Operating Temperature           | $T_C$     | 150         | °C   |
| Operating Junction Temperature (1,2) | $T_J$     | 225         | °C   |

**Table 2. Thermal Characteristics**

| Characteristic                       | Symbol          | Value (2,3) | Unit |
|--------------------------------------|-----------------|-------------|------|
| Thermal Resistance, Junction to Case | $R_{\theta JC}$ |             | °C/W |
| Case Temperature 80°C, 100 W CW      |                 | 0.53        |      |
| Case Temperature 75°C, 20 W CW       |                 | 0.59        |      |

1. Continuous use at maximum temperature will affect MTTF.
2. MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
3. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

**Table 3. ESD Protection Characteristics**

| Test Methodology                      | Class        |
|---------------------------------------|--------------|
| Human Body Model (per JESD22-A114)    | 3A (Minimum) |
| Machine Model (per EIA/JESD22-A115)   | A (Minimum)  |
| Charge Device Model (per JESD22-C101) | IV (Minimum) |

**Table 4. Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

| Characteristic  | Symbol    | Min | Typ | Max | Unit            |
|---|-----------|-----|-----|-----|-----------------|
| <b>Off Characteristics</b>  |           |     |     |     |                 |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 68\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ ) | $I_{DSS}$ | —   | —   | 10  | $\mu\text{Adc}$ |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 28\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ ) | $I_{DSS}$ | —   | —   | 1   | $\mu\text{Adc}$ |
| Gate-Source Leakage Current<br>( $V_{GS} = 5\text{ Vdc}$ , $V_{DS} = 0\text{ Vdc}$ )              | $I_{GSS}$ | —   | —   | 1   | $\mu\text{Adc}$ |

**On Characteristics**

|   |              |     |      |     |     |
|---|--------------|-----|------|-----|-----|
| Gate Threshold Voltage<br>( $V_{DS} = 10\text{ Vdc}$ , $I_D = 250\ \mu\text{Adc}$ )                             | $V_{GS(th)}$ | 1   | 2    | 3   | Vdc |
| Gate Quiescent Voltage<br>( $V_{DD} = 28\text{ Vdc}$ , $I_D = 1000\ \text{mAdc}$ , Measured in Functional Test) | $V_{GS(Q)}$  | 2   | 2.8  | 4   | Vdc |
| Drain-Source On-Voltage<br>( $V_{GS} = 10\text{ Vdc}$ , $I_D = 2.2\ \text{Adc}$ )                               | $V_{DS(on)}$ | 0.1 | 0.21 | 0.3 | Vdc |

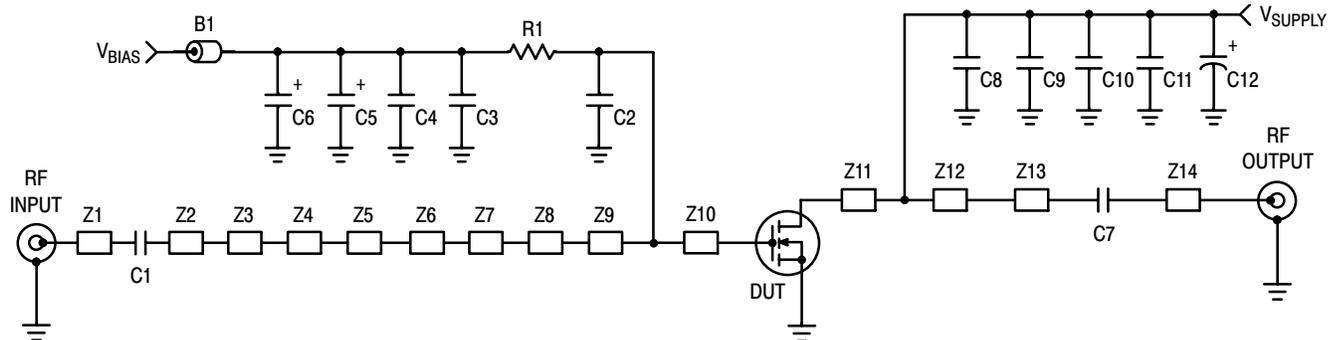
**Dynamic Characteristics (1)**

|  |           |   |     |   |    |
|--|-----------|---|-----|---|----|
| Reverse Transfer Capacitance<br>( $V_{DS} = 28\text{ Vdc} \pm 30\ \text{mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$ ) | $C_{rss}$ | — | 1.5 | — | pF |
|--|-----------|---|-----|---|----|

**Functional Tests** (In Freescale Test Fixture, 50 ohm system)  $V_{DD} = 28\text{ Vdc}$ ,  $I_{DQ} = 1000\ \text{mA}$ ,  $P_{out} = 20\ \text{W Avg.}$ ,  $f_1 = 2390\ \text{MHz}$ ,  $f_2 = 2400\ \text{MHz}$ , 2-Carrier W-CDMA, 3.84 MHz Channel Bandwidth Carriers. ACPR measured in 3.84 MHz Channel Bandwidth @  $\pm 5\ \text{MHz}$  Offset. IM3 measured in 3.84 MHz Bandwidth @  $\pm 10\ \text{MHz}$  Offset. PAR = 8.5 dB @ 0.01% Probability on CCDF.

|                              |          |      |       |    |     |
|------------------------------|----------|------|-------|----|-----|
| Power Gain                   | $G_{ps}$ | 14   | 15.4  | 17 | dB  |
| Drain Efficiency             | $\eta_D$ | 22.5 | 23.5  | —  | %   |
| Intermodulation Distortion   | IM3      | -35  | -37   | —  | dBc |
| Adjacent Channel Power Ratio | ACPR     | -38  | -40.5 | —  | dBc |
| Input Return Loss            | IRL      | —    | -10   | —  | dB  |

1. Part is internally matched both on input and output.



|    |                            |     |  |
|----|----------------------------|-----|--|
| Z1 | 0.725" x 0.080" Microstrip | Z9  | 0.329" x 0.756" Microstrip                                 |
| Z2 | 0.240" x 0.080" Microstrip | Z10 | 0.083" x 0.756" Microstrip                                 |
| Z3 | 0.110" x 0.240" Microstrip | Z11 | 0.092" x 0.800" Microstrip                                 |
| Z4 | 0.140" x 0.080" Microstrip | Z12 | 0.436" x 0.800" Microstrip                                 |
| Z5 | 0.167" x 0.500" Microstrip | Z13 | 0.974" x 0.080" Microstrip                                 |
| Z6 | 0.130" x 0.080" Microstrip | Z14 | 0.727" x 0.080" Microstrip                                 |
| Z7 | 0.250" x 0.611" Microstrip | PCB | Arlon CuClad 250GX-0300-55-22, 0.030", $\epsilon_r = 2.55$ |
| Z8 | 0.060" x 0.080" Microstrip |     |  |

**Figure 1. MRF6S23100HR3(HSR3) Test Circuit Schematic**

**Table 5. MRF6S23100HR3(HSR3) Test Circuit Component Designations and Values**

| Part           | Description                              | Part Number        | Manufacturer     |
|----------------|--|--------------------|------------------|
| B1             | Ferrite Bead, Surface Mount              | 2743019447         | Fair-Rite        |
| C1, C2, C7, C8 | 5.6 pF Chip Capacitors, B Case           | ATC100B5R6CT500XT  | ATC              |
| C3             | 0.01 $\mu$ F Chip Capacitor              | C1825C103J1RAC     | Kemet            |
| C4, C9         | 2.2 $\mu$ F, 50 V Chip Capacitors        | C1825C225J5RAC     | Kemet            |
| C5             | 22 $\mu$ F, 25 V Tantalum Capacitor      | T491D226K025AT     | Kemet            |
| C6             | 47 $\mu$ F, 16 V Tantalum Capacitor      | T491D476K016AT     | Kemet            |
| C10, C11       | 10 $\mu$ F, 50 V Chip Capacitors         | GRM55DR61H106KA88B | Murata           |
| C12            | 330 $\mu$ F, 63 V Electrolytic Capacitor | EMVY630GTR331MMH0S | Nippon Chemi-Con |
| R1             | 10 $\Omega$ , 1/4 W Chip Resistor        | CRC120610R0FKEA    | Vishay           |

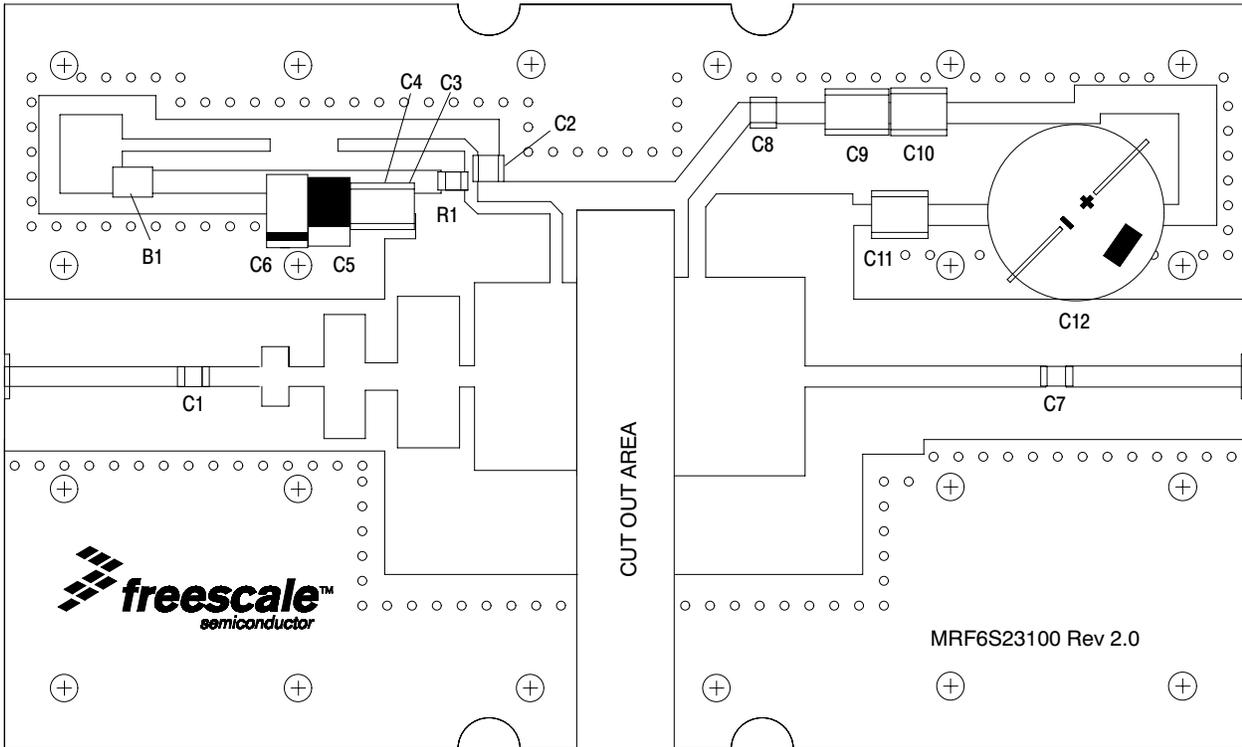
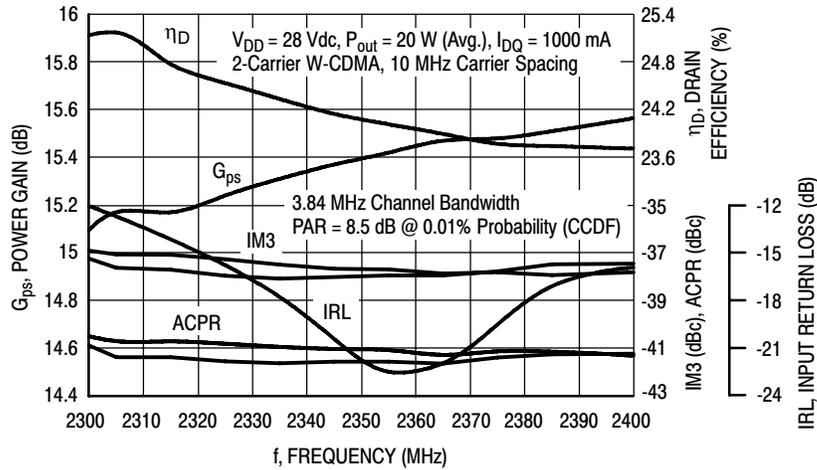
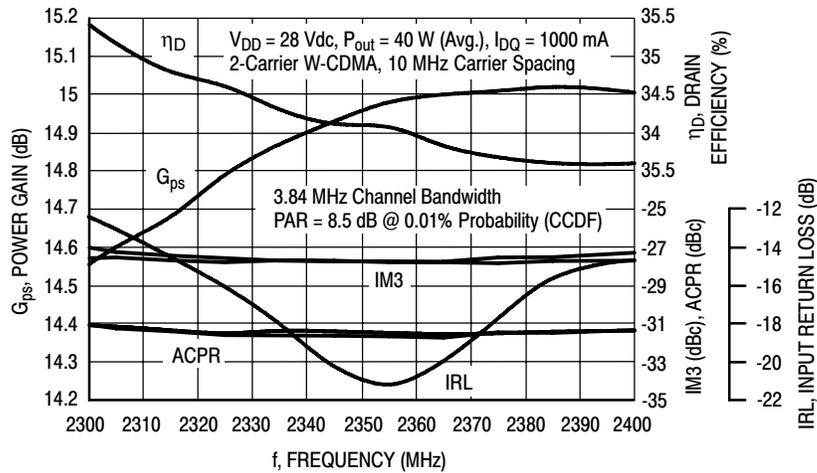


Figure 2. MRF6S23100HR3(HSR3) Test Circuit Component Layout

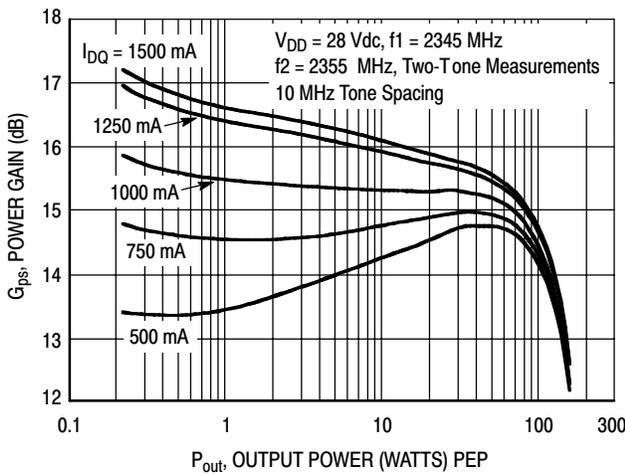
## TYPICAL CHARACTERISTICS



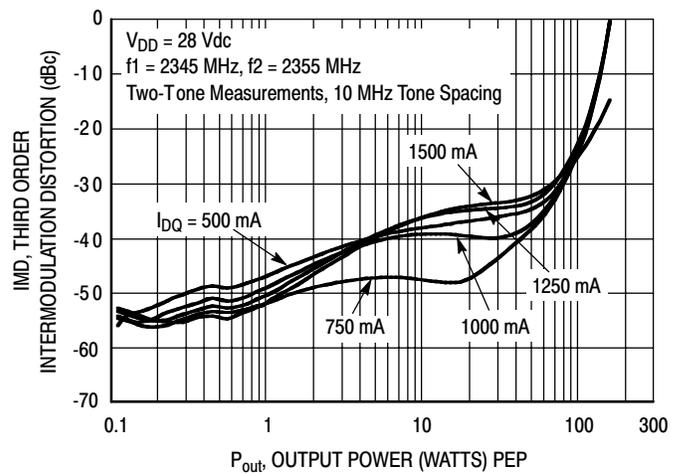
**Figure 3. 2-Carrier W-CDMA Broadband Performance @  $P_{out} = 20$  Watts Avg.**



**Figure 4. 2-Carrier W-CDMA Broadband Performance @  $P_{out} = 40$  Watts Avg.**

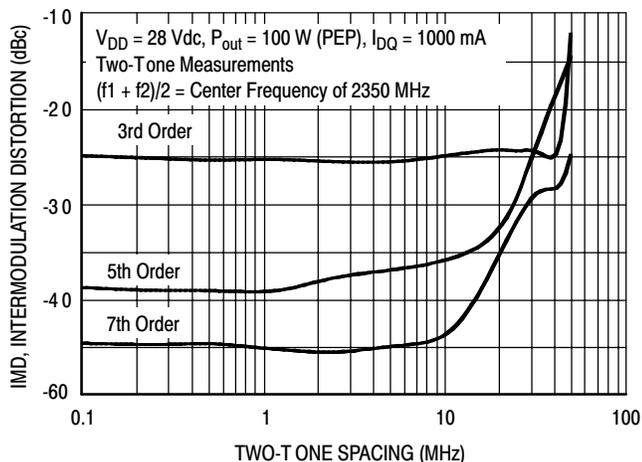


**Figure 5. Two-Tone Power Gain versus Output Power**

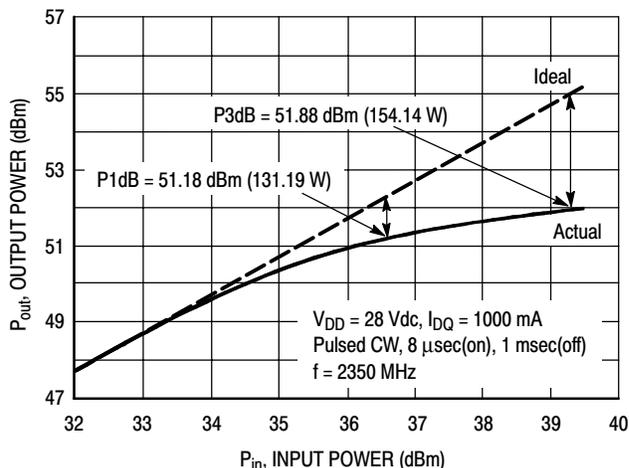


**Figure 6. Third Order Intermodulation Distortion versus Output Power**

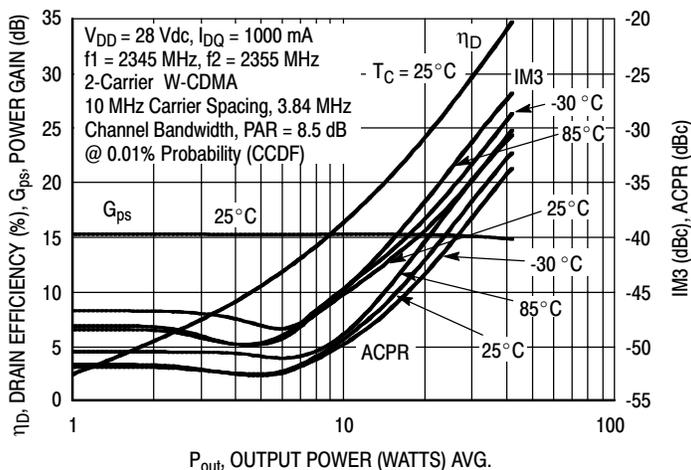
## TYPICAL CHARACTERISTICS



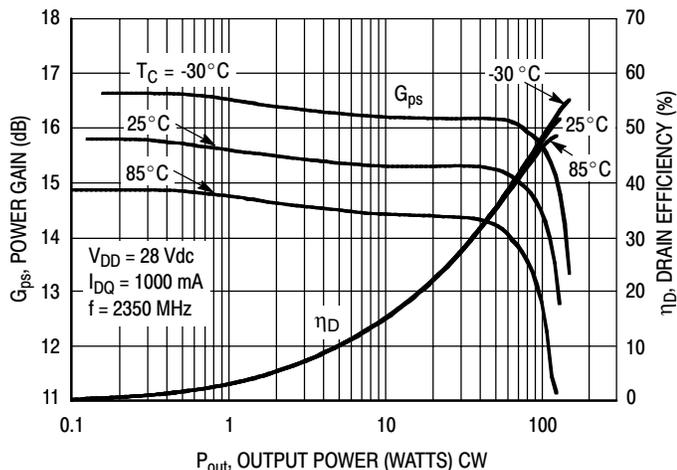
**Figure 7. Intermodulation Distortion Products versus Tone Spacing**



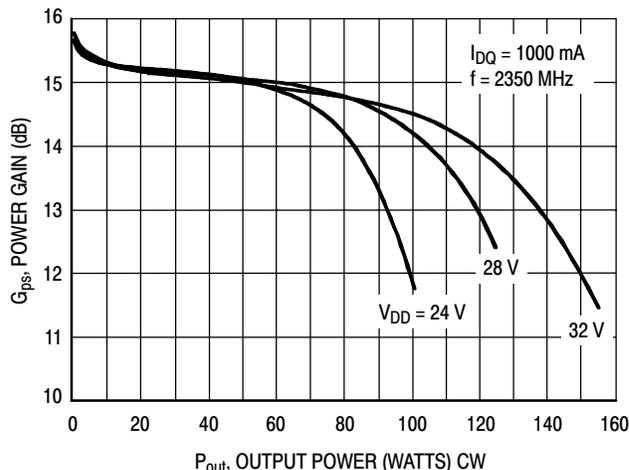
**Figure 8. Pulsed CW Output Power versus Input Power**



**Figure 9. 2-Carrier W-CDMA ACPR, IM3, Power Gain and Drain Efficiency versus Output Power**

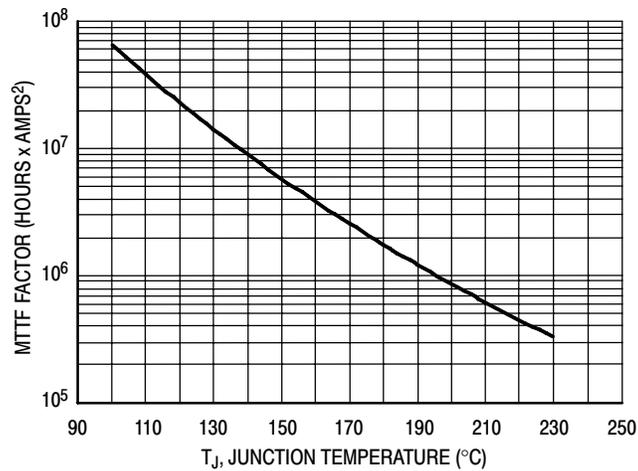


**Figure 10. Power Gain and Drain Efficiency versus CW Output Power**



**Figure 11. Power Gain versus Output Power**

## TYPICAL CHARACTERISTICS

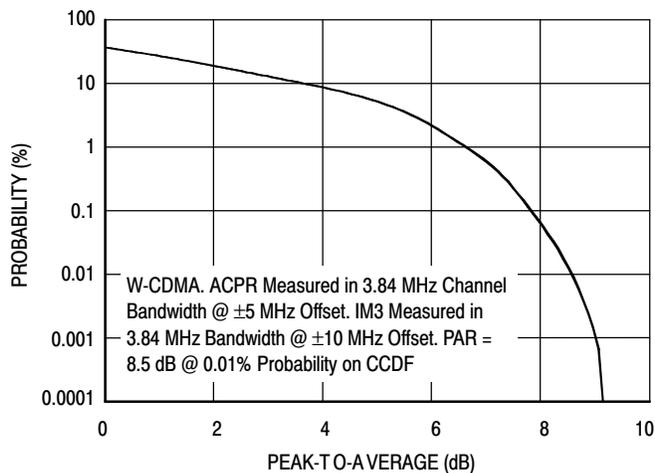


This above graph displays calculated MTTF in hours when the device is operated at  $V_{DD} = 28$  Vdc,  $P_{out} = 20$  W Avg., and  $\eta_D = 23.5\%$ .

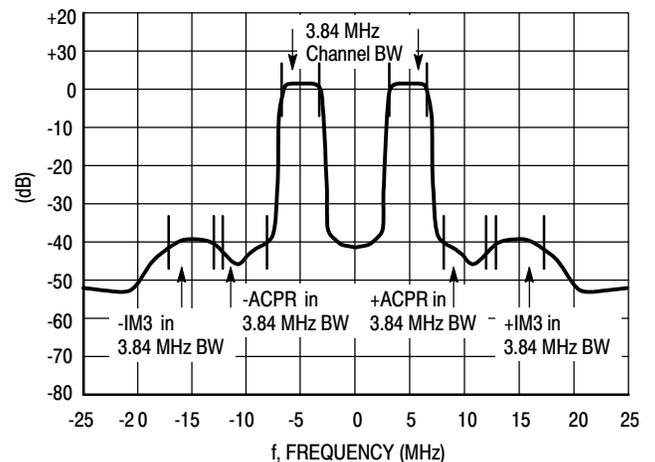
MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.

**Figure 12. MTTF Factor versus Junction Temperature**

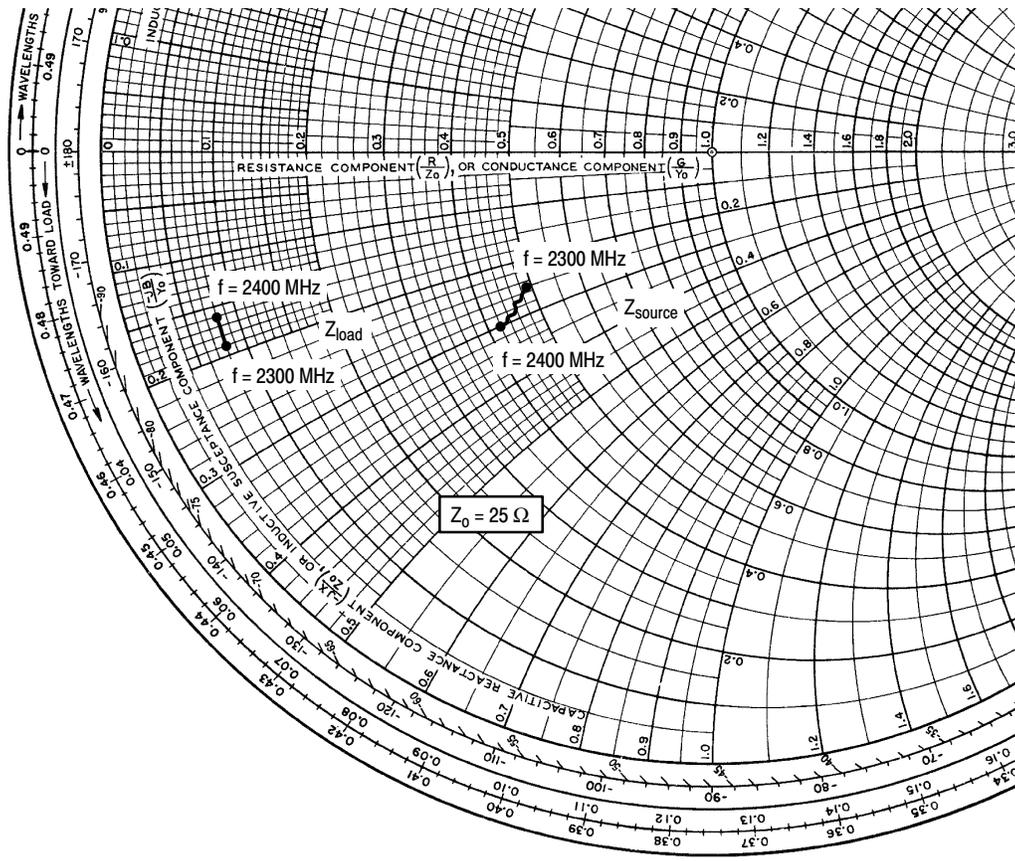
## W-CDMA TEST SIGNAL



**Figure 13. CCDF W-CDMA 3GPP, Test Model 1, 64 DPCH, 67% Clipping, Single-Carrier Test Signal**



**Figure 14. 2-Carrier W-CDMA Spectrum**



$V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 1000 \text{ mA}$ ,  $P_{out} = 20 \text{ W Avg.}$

| f<br>MHz | $Z_{source}$<br>$\Omega$ | $Z_{load}$<br>$\Omega$ |
|----------|--------------------------|------------------------|
| 2300     | 12.20 - j6.20            | 2.06 - j4.69           |
| 2310     | 12.06 - j6.40            | 2.04 - j4.62           |
| 2320     | 11.91 - j6.56            | 2.02 - j4.55           |
| 2330     | 11.76 - j6.71            | 2.01 - j4.48           |
| 2340     | 11.60 - j6.86            | 1.99 - j4.42           |
| 2350     | 11.44 - j7.00            | 1.97 - j4.35           |
| 2360     | 11.27 - j7.13            | 1.96 - j4.28           |
| 2370     | 11.10 - j7.22            | 1.94 - j4.22           |
| 2380     | 10.92 - j7.34            | 1.93 - j4.15           |
| 2390     | 10.73 - j7.46            | 1.91 - j4.09           |
| 2400     | 10.55 - j7.53            | 1.90 - j4.02           |

$Z_{source}$  = Test circuit impedance as measured from gate to ground.

$Z_{load}$  = Test circuit impedance as measured from drain to ground.

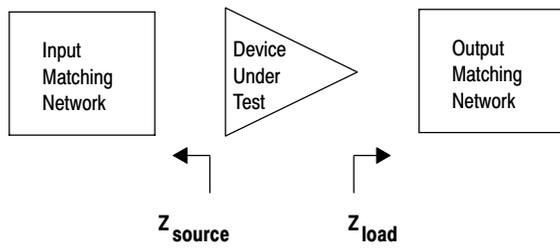
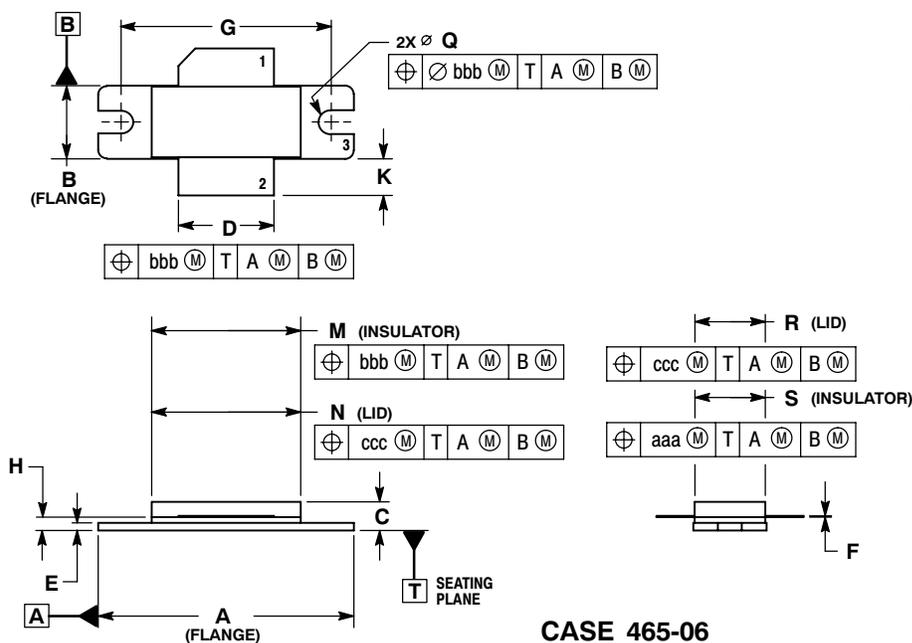


Figure 15. Series Equivalent Source and Load Impedance

## PACKAGE DIMENSIONS

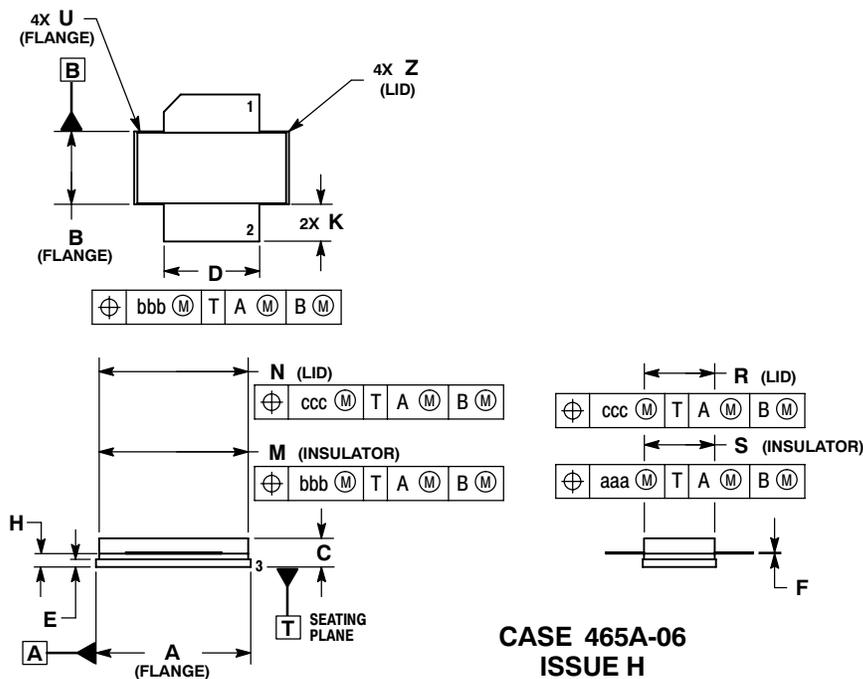


- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
  2. CONTROLLING DIMENSION: INCH.
  3. DELETED
  4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

| DIM | INCHES    |       | MILLIMETERS |       |
|-----|-----------|-------|-------------|-------|
|     | MIN       | MAX   | MIN         | MAX   |
| A   | 1.335     | 1.345 | 33.91       | 34.16 |
| B   | 0.380     | 0.390 | 9.65        | 9.91  |
| C   | 0.125     | 0.170 | 3.18        | 4.32  |
| D   | 0.495     | 0.505 | 12.57       | 12.83 |
| E   | 0.035     | 0.045 | 0.89        | 1.14  |
| F   | 0.003     | 0.006 | 0.08        | 0.15  |
| G   | 1.100 BSC |       | 27.94 BSC   |       |
| H   | 0.057     | 0.067 | 1.45        | 1.70  |
| K   | 0.170     | 0.210 | 4.32        | 5.33  |
| M   | 0.774     | 0.786 | 19.66       | 19.96 |
| N   | 0.772     | 0.788 | 19.60       | 20.00 |
| Q   | Ø.118     | Ø.138 | Ø3.00       | Ø3.51 |
| R   | 0.365     | 0.375 | 9.27        | 9.53  |
| S   | 0.365     | 0.375 | 9.27        | 9.52  |
| aaa | 0.005 REF |       | 0.127 REF   |       |
| bbb | 0.010 REF |       | 0.254 REF   |       |
| ccc | 0.015 REF |       | 0.381 REF   |       |

- STYLE 1:  
 PIN 1. DRAIN  
 2. GATE  
 3. SOURCE

**CASE 465-06  
 ISSUE G  
 NI-780  
 MRF6S23100HR3**



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
  2. CONTROLLING DIMENSION: INCH.
  3. DELETED
  4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

| DIM | INCHES    |       | MILLIMETERS |       |
|-----|-----------|-------|-------------|-------|
|     | MIN       | MAX   | MIN         | MAX   |
| A   | 0.805     | 0.815 | 20.45       | 20.70 |
| B   | 0.380     | 0.390 | 9.65        | 9.91  |
| C   | 0.125     | 0.170 | 3.18        | 4.32  |
| D   | 0.495     | 0.505 | 12.57       | 12.83 |
| E   | 0.035     | 0.045 | 0.89        | 1.14  |
| F   | 0.003     | 0.006 | 0.08        | 0.15  |
| H   | 0.057     | 0.067 | 1.45        | 1.70  |
| K   | 0.170     | 0.210 | 4.32        | 5.33  |
| M   | 0.774     | 0.786 | 19.61       | 20.02 |
| N   | 0.772     | 0.788 | 19.61       | 20.02 |
| R   | 0.365     | 0.375 | 9.27        | 9.53  |
| S   | 0.365     | 0.375 | 9.27        | 9.52  |
| U   | ---       | 0.040 | ---         | 1.02  |
| Z   | ---       | 0.030 | ---         | 0.76  |
| aaa | 0.005 REF |       | 0.127 REF   |       |
| bbb | 0.010 REF |       | 0.254 REF   |       |
| ccc | 0.015 REF |       | 0.381 REF   |       |

- STYLE 1:  
 PIN 1. DRAIN  
 2. GATE  
 5. SOURCE

**CASE 465A-06  
 ISSUE H  
 NI-780S  
 MRF6S23100HSR3**

## PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

### Application Notes

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

### Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

## REVISION HISTORY

The following table summarizes revisions to this document.

| Revision | Date      | Description  |
|----------|-----------|--|
| 2        | Dec. 2008 | <ul style="list-style-type: none"><li>• Modified data sheet to reflect RF Test Reduction described in Product and Process Change Notification number, PCN13232, p. 1, 2</li><li>• Removed Lower Thermal Resistance and Low Gold Plating bullets from Features section as functionality is standard, p. 1</li><li>• Removed Total Device Dissipation from Max Ratings table as data was redundant (information already provided in Thermal Characteristics table), p. 1</li><li>• Operating Junction Temperature increased from 200°C to 225°C in Maximum Ratings table and related "Continuous use at maximum temperature will affect MTTF" footnote added, p. 1</li><li>• Corrected <math>V_{DS}</math> to <math>V_{DD}</math> in the RF test condition voltage callout for <math>V_{GS(Q)}</math>, On Characteristics table, p. 2</li><li>• Removed Forward Transconductance from On Characteristics table as it no longer provided usable information, p. 2</li><li>• Updated PCB information to show more specific material details, Fig. 1, Test Circuit Schematic, p. 3</li><li>• Updated Part Numbers in Table 5, Component Designations and Values, to latest RoHS compliant part numbers, p. 3</li><li>• Adjusted scale for Fig. 7, Intermodulation Distortion Products versus Tone Spacing, to show wider dynamic range, p. 6</li><li>• Removed lower voltage tests from Fig. 11, Power Gain versus Output Power, due to fixed tuned fixture limitations, p. 6</li><li>• Replaced Fig. 12, MTTF versus Junction Temperature with updated graph. Removed Amps<sup>2</sup> and listed operating characteristics and location of MTTF calculator for device, p. 7</li><li>• Added Product Documentation and Revision History, p. 10</li></ul> |

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